

3/10/09

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250132US2TTCRD DIV		SERIAL NO. 10/796,086 New DIV Appln.	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT					
		Shiho OKUNO, et al.					
		FILING DATE		Herewith		GROUP Art Unit 3729	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ADT	AA	6,469,926	10-2002	Chen, Eugene Youjun	-	-	
ADT	AB	2001/0009063	07/2001	Saito et al.	-	-	
ADT	AC	2002/0051380	05/2002	Kamiguchi et al.	-	-	
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
ADT	AO	JP 2000-293982	10-2000	Japan	YES	NO	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
ADT	AW	N. GARCIA, et al., "Magnetoresistance in Excess of 200% in Ballistic Ni Nanocontacts at Room Temperature and 100 Oe," PHYSICAL REVIEW LETTERS, Vol. 82, No. 14, April 5, 1999, pp. 2923-2926					
ADT	AX	J.J. VERSLUIS, et al., "Magnetoresistance of Half-Metallic Oxide Nanocontacts," PHYSICAL REVIEW LETTERS, Vol. 87, No. 2, July 9, 2001, pp. 026601-1 through 026601-4					
	AY						
	AZ	<input type="checkbox"/> Additional References sheet(s) attached					
Examiner /A. Dexter Tugbang/				Date Considered 9/30/06			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250132US2RD DIV		SERIAL NO. 10/796,086	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Shiho OKUNO, et al.		SEP 05 2006 U.S. PATENT & TRADEMARK OFFICE	
		FILING DATE		March 10, 2004		GROUP 3729	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	ADT	AO 11-510911	09/21/99	Japan	YES	NO	x
		AP 02-173278	07/04/90	Japan (with English abstract)			x
		AQ 11-293481	10/26/99	Japan (with English abstract0			x
		AR 07-022399	01/24/95	Japan (with English abstract)			x
		AS 05-160123	06/25/93	Japan (with English abstract)			x
	ADT	AT WO 97/47982	12/18/97	WIPO			x
		AU					
		AV					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
							<input type="checkbox"/> Additional References sheet(s) attached
Examiner /A. Dexter Tugbang/					Date Considered 9/30/06		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							